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Infrared Imaging Systems: Design, Analysis, Modeling, and Testing XXX

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Keith A. Krapels
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Introduction

This is the 30th year for our conference, Infrared Imaging Systems: Design, Analysis, Modeling, and Testing. Mike Soel provided an excellent walk down memory lane with is paper "**30 years of value engineering to the IR community.**" One of us (Gerald C. Holst) received an award for chairing all 30 conferences. There he is pictured below with the conference committee.

Left to right (standing); Richard Espinola, Endre Repasi, Katrin.Braesicke, Piet Bijl, Gerald Holst, Michael Soel, Eddie Jacobs, David Haefner, Orges Furxhi, Alan Irwin, Ronald Driggers (Sitting) Joseph Reynolds, James Dawson.

For time to time we have joint session with other conferences. Again, we teamed up with the long-range imaging conference chaired by Eric Kelmelis.

In 2016, our conference committee created two Best Paper awards. One based upon the presentation (selected by the conference committee) and the other, the most downloaded in the first 3 months after publication. The most downloaded paper represents the current hot topic. We recommend readers review these outstanding papers. The 2016 and 2017 papers are listed in the Introduction to SPIE Proceeding volume 10625 (2018).

2018
Best presentation
David P. Haefner, "MTF measurements, identifying bias, and estimating uncertainty" Proc. SPIE 10625, paper *1062506 (2018)*.

Most downloaded paper (first 3 months after publication)
Robert Nicholas, Ronald Driggers, David Shelton and Orges Furxhi, "Infrared search and track performance estimates for detection of commercial unmanned aerial vehicles." Proc. SPIE 10625, paper 106250Y (2018).

2019
Best presentation
Kevin J Miller, Bradley Preece. Todd du Bosq, Kevin Leornard, "A data-constrained algorithm for the emulation of long-range-turbulence-degraded video." Proc. SPIE 11001 paper 110010J *(2019)*.

Most downloaded paper (first 3 months after publication)
Brian P. Teaney, David P. Haefner, Stephen D. Burks, and Joshua M. Doe, "Evaluating the performance of reflective band imaging systems (a tutorial)," Proc. SPIE 11001 *(2019)*.

Thank you to all who presented, the attendees, our excellent conference committee, and SPIE.

Gerald C. Holst
Keith A. Krapels